

<b>Notice of References Cited</b>	Application/Control No. 10/005,193	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Fred I. Ehichioya	Art Unit 2172	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,754,667 B2	06-2004	Kim et al.	707/102
	B	US-6,751,343 B1	06-2004	Ferrell et al.	382/145
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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